XN0NE92

Silicon P-channel MOSFET (FET) Silicon epitaxial planar type (SBD)

For DC-DC converter

Features

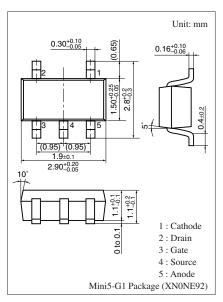
- Two elements incorporated into one package
- Reduction of the mounting area and assembly cost by one half
- High-speed switching, low on resistance

Basic Part Number

• DS1125 + MA2ZD12

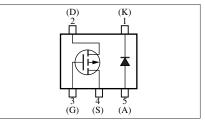
Absolute Maximum Ratings $T_a = 25^{\circ}C$

	Parameter	Symbol	Rating	Unit
FET	Drain-source surrender	V _{DSS}	-12	V
	voltage			
	Gate-source surrender	V _{GSS}	±15	V
	voltage			
	Drain current	I _D	-1.2	А
	Peak drain current	I _{DP}	-3	А
	Total power dissipation *	P _T	600	mW
	Channel temperature	T _{ch}	125	°C
	Storage temperature	T _{stg}	-55 to +125	°C
SBD	Reverse voltage	V _R	20	V
	Repetitive peak reverse voltage	V _{RRM}	25	V
	Forward current (Average)	I _{F(AV)}	700	mA
	Non-repetitive peak	I _{FSM}	2	А
	forward surge current			



Marking Symbol: 3F

Internal Connection



Note) *: Measuring on ceramic substrate at 15 mm \times 15 mm \times 0.6 mm

Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

• FET	
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Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source surrender voltage	V _{DSS}	$I_{C} = -1 \text{ mA}, V_{GS} = 0$	-12			V
Drain-source cutoff current	I _{DSS}	$V_{DS} = -10 V, V_{GS} = 0$			-1	V
Gate-source cutoff current	I _{GSS}	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0$			±10	V
Gate threshold voltage	V _{th}	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	- 0.4		-1.3	V
Forward transfer admittance *	Yfs	$V_{DS} = -10 \text{ V}, I_D = -800 \text{ mA}$	0.8	1.1		S
Drain-source ON resistance *	R _{DS(on)}	$V_{GS} = -4 V, I_D = -800 mA$		350	450	mΩ
Turn-on time	t _{on}	$V_{DD} = -10 \text{ V}, \text{ R}_{L} = 12.5 \Omega,$		15		ns
Storage time	t _{stg}	$I_D = -800 \text{ mA}, \text{ V}_{GS} = 0 \text{ V} \text{ to } -4 \text{ V}$		10		ns
Turn-off time	t _{off}			10		ns

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.
Observe precautions for handling. Electrostatic sensitive devices.

3. *: Pulse measurement

Electrical Characteristics (continued) $T_a = 25^{\circ}C \pm 3^{\circ}C$

• SBD

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	V _F	$I_F = 700 \text{ mA}$			0.45	V
Reverse current	IR	$V_R = 20 V$			200	μΑ
Terminal capacitance	Ct	$V_{R} = 0, f = 1 MHz$		100		pF
Reverse recovery time	t _{rr}	$I_F = I_R = 100 \text{ mA}$		7		ns
		$I_{rr} = 10 \text{ mA}, R_L = 100 \Omega$				

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 Measuring methods for diodes.

2. Schottky barrier diode is frail with static electricity, and it should be kept in safety from shock of static electricity and static electricity level.

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